

Docket No.: 60188-044

#7
C. B. B. 1217
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of :

Hirokazu YONEZAWA, et al. :

Serial No.: :

Group Art Unit:

Filed: March 19, 2001 :

Examiner:

For: APPARATUS AND METHOD FOR CALCULATING TEMPORAL DETERIORATION
MARGIN AMOUNT OF LSI, AND LSI INSPECTION METHOD



CLAIM OF PRIORITY

Commissioner for Patents
Washington, DC 20231

Sir:

In accordance with the provisions of 35 U.S.C. 119, Applicants hereby claim the priority of:

Japanese Patent Application No. 2000-076087,
filed March 17, 2000

A certified copy will be filed in due course.

Respectfully submitted,

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